MIL-E-1/83A 25 July 1956 SUPERSEDING MIL-E-1/83 5 Feb. 1953

INDIVIDUAL MILITARY SPECIFICATION SHEET

ELECTRON TUBE, MINIATURE XENON THYRATRON, TETRODE

JAN-5727/2D21W

This specification sheet forms a part of the latest issue of Military Specification MIL-E-l.

Ratings: Absolute Maximum:	Ef V	epp v	epy v	epx v	onductio Ec2 V	Ecl V	Non-Co ec2 v	onduction ecl v	ehk v	Rgl Meg	Rg2 Ohms Min	Max	
Relay, G con- trolled Rect.:	6.3/10%	_	650	1300	-10	-10	-100	-100	-100 / 25	10	1000		
Pulse Modulator:	6.3/10% - 5%	500 Note	500	100	-10	-10	- 50	-100	0	0.5	2000	25K	
Test. Cond.:	6.3				0			_				-	
Ratings: Absolute Maximum:	a i	Ik mA te 2	ig2 ma	igl ma	Ig2 mA Note 2	Igl mA Note 2	tp us	dik/dt a/us	prr pps	Du	OC DA		tk sec(min)
Relay, G. con- trolled Rect.:	0.5 1	00	_		10	10				_	-75 to #	90	20
Pulse Modulator:	10	10	20	20		_	5	100	500	.001	-75 to f	90	20
Test. Cond.:					-			_					20
	Unipote		in, E7-	1				2-1/8 in. x. 3/4 in.					
n: :: 1			/ -			73	m	10 // 01					

Pin No.: Element:

Envelope: T-5 1/2 (6-2)

The follow For miscel	ving tests shall be Llaneous requiremen	performed: ts, see Paragraph 3.3, Inspec	tion :	Instruc	tions	for E	lectr	on Tube	s.			
Ref.	Test	Conditions	AQL Le	Insp.	sym.	LIMITS						Units
				or Code		Min.	LAL	Bogie	UAL	Max.	ALD	
	Qualification App	proval Tests										
3.1	Qualification Approval:	Required for JAN Marking	_									
	Cathode:	Coated Unipotential										
3.4.3	Base Connections:	E7-1										
4.9.20.3	Vibration (1):	No Voltages										
	Measurements Acce	ptance Tests, Part 1, Note 3										
4.10.8	Heater Current:	Note 4			If:		565	600	635		52	mA
4.10.8	Heater Current:		0.65	II	If:	540				660		mA.
4.10.15	Heater-Cathode Leakage:	Ehk= ≠25 Vdc Ehk= -100 Vdc	0.65 0.65		Ihk: Ihk:	=	=	=	=	15 15	=	uAdc uAdc

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	200.00	Conditions	AQL	Insp. Level			L	IMI TS	0			11-24
Ref.	Test	Conditions	(%)	or Code	Sym.	Min.	LAL	Bogie	UAL	Max.	ALD	Unit
	Measurements Acce	ptance Tests, Part 1,										
4.10.17.1	Grid Voltage(1);	Epp=460 Vac; Rgl=0.1 Meg; Rp=3000; Notes 4, 6, and 7			Eccl:		-3.4	-3.7	-4. 0	•	•70	Vdc
4.10.17.1	Grid Voltage(1):	Epp=460 Vac; Rgl=0.1 Meg; Rp=3000; Notes 6 and 7	0,65	11	Eccl:	-2.9				-4.5		Vdc
4.10.17.1	Grid Voltage(2):	Epp=460 Vac; Rgl=10 Meg; Rp=3000; Notes 6 and 7	0.65	II	Eccl:	-		-4.2		-5.2		Vdc
4.10.17.2	Anode Voltage(1):	Eccl=0; Rgl=0.1 Meg; Rp=1000; Notes 4, 6, and 9			Ebb:			29	33		8.0	Vdc
4.10.17.2	Anode Voltage(1):	Eccl=0; Rgl=0.1 Meg; Rp=1000; Notes 6 and 9	0.65	·II	Ebb:	-		_	-	38		Vdc
4.10.17.2	Anode Voltage(2):	Ef=0; Eccl=-100 Vdc; Rgl=0; Rp=10,000; Notes 6 and 10	0.65	13-	Ebb:	650						Vdc
	Operation:	Ebb=500 Vdc approx.; egy=100 v; epy=1000 v; Eccl=50 Vdc; Ecc2=0; prr=500 pps; Zo=25; RL=20; Note 31	0.65	п	ib:	16						а
4.10.24	Pulse Emission:	Ef=6.3 Vac; epp=eggl=egg2= 180 £ 9 v;tp=5£0.25us; tr=0.5 us (max); tf=1.0 us (max); prr=100 £ 5 pps; Note 21	0.65	II	etd:			_		76		v
4.7.5	Continuity and Shorts: (Inoperatives)	Note 22	0.4	п			-	-				
4.9.1	Mechanical:	Envelope Outline No. (6-2)					_	_	_		_	
	Measurements Acce	ptance Tests, Part 2										
4.8	Insulation of Electrodes:	Ef=6.3 V; Note 23; Eg2-p= <u>/</u> 380 Vdc	2.5	IA	Rg2-p:	760	-		_			Meg
4.10.17.2	Anode Voltage(3):	Ef=5.7 V; Eccl=0; Rgl=0.1 Meg; Rp=1000; Notes 6, 9 and 24	2.5	II	Ebb:		-		_	50		Vdc

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	Test	Conditions	AQL	Insp. Level		LIMITS						
Ref.			(%)	or Code	Sym.	Min.	LAL	Bogie	UAL	Max.	ALD	Units
		ptance Tests, Part 2 tinued)										
4.10.17.1	Grid Voltage(3):	Ef=7.0 V; Epp=4.60 Vac; Rgl=10 Meg; Rp=3000; Notes 6, 7 and 25.	6.5	IA	Eccl:					-6.4		Vdc
	Grid #2 Voltage:	Epp=150 Vac; Egg1=16 Vac; Rp=1000; Rg1=2500; Notes 26 and 27	6.5	IA	Egg2:	1.9		2.6		3.3		Vac
4.9.19.1	Vibration(2):	No Voltages	6.5	I				-				
is .	Degradation Rate	Acceptance Tests, Note 8										
4.9.20.5	Shock:	Hammer Angle=480	20					-				
4.9.20.6	Fatigue:	G=2.5; F=25 min, 60 max; Fixed Frequency	6.5	Note 5		_	-	-				
	Post Shock and Fatigue Test End Points:	Heater—Cathode Leakage Ehk=\frac{25}{25} Vdc Ehk=\frac{100}{25} Vdc Anode Voltage(1) Pulse Emission Grid Voltage(1)		=======================================	Ihk: Ihk: Ebb: etd: Eccl:	-2.9	=	=	=	40 40 50 76 -4•5	=======================================	uAdc uAdc Vdc V Vdc
	Glass Strain:	Note 11	2.5	I						_		
4.9.6.1	Glass Strain:		_			-	_	_		_	_	

	*	Α.	AQL	Insp.	tive	ole Defec- es per c'eristic		LIM	ITS	
Ref.	<u>Test</u>	Conditions	(%)	or Code	lst	Combined Sample	Sym.	Min.	Max.	Units
	Acceptance Life Tests,	Note 8								
4.11.7	Heater Cycling Life Test:	Ef=7.5 V; Ehk= -100; Ecl=Ec2=Eb=0; Note 12	1.0							
4.11.4	Heater Cycling Life Test End Points:	Heater-Cathode Leakage Ehk= /25 Vdc Ehk= -100 Vdc	=	=	_	=	Ihk: Ihk:	=	20 20	uAdc uAdc
-	Stability Life Test: (1 hour)	Epp=460 Vac;Rp/Tb=80mAdd (min); Rgl=50,000; Rp/ib=500 ma (min); TA Room;tk=20 sec; Notes 6, 13 and 28	1.0	I					-	
4.11.4	Stability Life Test End Points:	Grid Voltage(1)		_	_		Eccl:	-2.8	-4.6 15%	Vdc
-	Survival Rate Life Test: (100 hours)	Stability Life Test Conditions or equivalent; Notes 6, 14, 15, 28 and 30	_	п		_				
4.11.4	Survival Rate Life Test End Points:	Continuity and Shorts Grid Voltage(1)	0.65	=	=	_	Eccl:	-2.0	<u>-4.</u> 8	Vdc
4.11.5	Intermittent Life Test:	Stability Life Test Conditions; T Envelope=150°C min; Notes 6, 16, 17 and 28		-		_				76
4.11.4	Intermittent Life Test End Points: (500 hours)	Note 18 Inoperatives; Note 19 Heater Current Grid Voltage(1) Anode Voltage(1) Pulse Emission Heater-Cathode Leakage	=	=	1 1 1 2	3 3 3 3 5	If: Eccl: Ebb: etd:	540 -2.0	670 -4.8 50 100	mA Vdc Vdc v
		Ehk= -25 Vdc Ehk= -100 Vdc Insulation of Electrode			1	3	Ihk: Ihk:	=	20 20	uAdc uAdc
		g2-p			2	5	R:	380		Meg
		Total Defectives	_	_	4	8				
4.11.4	Intermittent Life Test End Points: (1000 hours)	Inoperatives; Note 19 Heater Current Grid Voltage(1) Heater-Cathode Leakage	=	=	2 2 2	5 5 5	If: Eccl:	540 -1.6	680 -4.8	mA Vdc
		Ehk= / 25 Vdc Ehk= -100 Vdc			2	5	Ihk: Ihk:	_	20 20	uAdc uAdc
		Total Defectives	_		5	10		_		

	<u>Test</u>	<u>Conditions</u>	AQL	Insp.	tive	ole Defec- es per eteristic	Sym.	LIN	Units	
Ref.			(%)	Code	lst Sample	Combined. Sample	Sym.	Min.	Max.	
4.11	Acceptance Life Tests Continuous Life Test; (200 hours)									e.
4.11.4	Continuous Life Test End Points:	Pulse Emission Continuous Life Test conditions; Note 20					etd: ib:	16	100	V a
4.9.18.1.6	Packaging Requirement Container Drop:	(d) Package, Group 1; Carton Size B								

- Note 1: After completion of a pulse, a 20 us delay is required before a positive voltage of more than 10 v is applied to the tube.
- Note 2: Averaged over any interval of 30 seconds maximum.
- Note 3: The ACL for the combined defectives for attributes in Measurements Acceptance Tests, Part 1, excluding Inoperatives and Mechanical shall be one (1) percent. A tube having one (1) or more defects shall be counted as one (1) defective. MIL-SID-105, Inspection Level II shall apply.
- Note 4: Variables Sampling Procedure:

Test for Lot Average Acceptance, Using Mean:
Select a 35 tube sample at random from the lot. Number these tubes consecutively.

Determine the numerical average value of the characteristic as specified on the specification sheet of the 35 tube sample. If this value is on or above the LAL and on or below the UAL, accept for Lot Average.

Test for Lot Dispersion Acceptance, Using Average Range:
Divide the 35 tube sample into seven (7) consecutive sub-groups of five (5) tubes each. Determine the range, R, of each sub-group for the measured characteristic specified on the Tube Specification Sheat

Compute the \overline{R} which is the average of the R values. If \overline{R} is equal to or less than the ALD, accept for Lot Dispersion.

Alternate Method, Variables Sampling Procedure:

Test for Lot Average Acceptance, Using Median: Select a 35 tube sample at random from the lot.

Test for all electrical characteristics for which variable acceptance limits are shown on the TSS.

Arrange the 35 measurements in the order of magnitude.

Find the value of the 18th measurement of the sample so arranged. This is the median (X) of the sample of 35.

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Note 4 : (Contd)

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If (X) is on or above the LAL and on or below the UAL, accept for lot average.

Test for Lot Dispersion Acceptance, Using Quasi-Range: Arrange the 35 measurements in order of magnitude.

Find the difference between the 3rd and 33rd measurements of the samples so arranged. This is the quasi-range (QR3) of the sample of 35.

Multiply this quasi-range by 0.83.

If CR3 multiplied by 0.83 is equal to or less than the ALD, accept the characteristic for lot dispersion.

- Note 5: This test shall be conducted on the initial lot and thereafter on a lot approximately every 30 days. Once a lot has passed, the 30-day rule shall apply. In the event of lot failure, the lot shall be rejected and the succeeding lot shall be subjected to this test. MIL-STD-105, sample size code letter F shall apply.
- Note 6: Connect Pins 5 and 7 to Pin 2.
- Use miniature steatite socket with grounded shield base. Shield the plate power supply. Use short shielded plate and grid leads. Plate and grid resistors shall be noninductive. the grid resistor directly at the socket.
- Note 8: Destructive Tests:
 Tubes subjected to the following destructive tests are not to be accepted under this specification.

4.9.20.5 4.9.20.6 Fatigue

Heater-Cycling Life Test Intermittent Life Test Continuous Life Test 4.11.5 4.11

- Note 9: Increase Ebb supply slowly and read Ebb at which conduction occurs.
- Note 10: No voltages shall be applied to tube for 20 minutes minimum preceding this test.
- Glass Strain Procedures All tubes submitted to this test shall have been sealed a minimum of Note 11: Glass Strain Procedures - All tubes submitted to this test shall have been sealed a minimum of 48 hours prior to conducting this test. All tubes shall be at room temperature. The entire tube shall be immersed in water not less than 97°C for 15 seconds and immediately thereafter immersed in water not more than 5°C, for 5 seconds. The volume of water shall be large enough so that the temperature will not be appreciably affected by the test. The method of submersion shall be in accordance with Drawing #245-JAN, and such that a minimum of heat is conducted away by the holder used. The tubes shall be placed in the water so that no contact is made with the containing used. The tubes shall be placed in the water so that no contact is made with the containing vessel, nor shall the tubes contact each other. After the 5-second submersion period, the tubes shall be removed and allowed to dry at room temperature on a wooden surface. After drying at room temperature for a period of 48 hours, the tubes shall be inspected and rejected for evidence of air leaks. Electrical rejects, other than inoperatives, may be used in the performance of this test. The statement in "Inspection Instructions for Electron Tubes", paragraph 5.3.6.1, which defines an air leak as "*any tube which shows a grid current of 1.0 undo or twice the maximum limit, which will be employed as incorrection to the statement of the st whichever is greater, shall be considered an inoperative" shall not apply.
- Note 12: The no-load to steady state full load regulation of the heater voltage supply shall be not more than 3.0 percent. This test shall be made on a lot by lct basis. A failure or defect shall consist of an open heater, open cathode circuit, heater cathode short, or heater cathode leakage current in excess of the specified heater cycling life test end point limit.
- Note 13:
 - Stability Life Test:
 a. Life test samples shall be selected from a lot at random in such a manner as to be representative of the lot. If such selection results in a sample containing tubes which are outside the initial specification sheet limits for the relevant life test end point characteristic, such tubes shall be replaced by randomly selected acceptable tubes.
 - Serially mark all tubes from the sample.

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Note 13: (Contd)

- Record referenced characteristic measurements after a maximum operation of 15 minutes under specified voltage and current conditions on the entire sample.
- Operate at life test conditions for one (1) hour (plus 30 minutes, minus 0 minutes). Life test shall be conducted as per paragraphs 4.11 and 4.11.5, MIL-E-1, except that the following shall be substituted for the third sentence of 4.11: The mean electrode potentials, except heater or filament, may be established at values differing by not more than 5% from the specified values provided the same average anode current is obtained that occurs with the specified voltages. Fluctuations of all voltages including heater or filament voltage shall be as small as practical.
- Record referenced characteristic measurements at the end of this test period. Referenced characteristic measurements shall be taken immediately following the test or tubes shall be preheated 15 minutes under specified test voltages and current conditions, and immediately measured. The 15 minutes preheat shall be considered as part of the test time.
- f. A defective shall be defined as a tube having a change in referenced characteristic greater than that specified on the specification sheet.
- A resubmitted lot must be subjected to all Measurements-Acceptance Tests except Mechanical Inspection and Vibration tests.

Note 14:

Means of Assuring Survival Rate - The procedure for assuring the maintenance of a desirable quality level in terms of early life survival consists of a series of normal, reduced, and tightened inspection plans for use at 100 hours. The sample size is dependent upon lot size, and the transfer between normal, reduced, and tightened inspection is dependent upon quality history.

The selection of inspection scheme and sampling plan shall be in accordance with Inspection Instructions for Electron Tubes paragraph 5.3.4.2 through 5.3.4.3.1.3 inclusive except that paragraph 5.3.4.2.2 shall be modified by deleting the last part of the first sentence which states "... or if no lot in the last 20 lots inspected shall have been declared nonconforming for life test qualities". At the manufacturer's option, reduced inspection may be used if no lot in the last ten (10) lots inspected have been declared nonconforming.

Inspection Procedure:

- Select sample in accordance with Note 13, paragraph (a).
- b. Tubes to be tested at 100 hours as provided in MIL-E-1 (4.7.5). When any tap-short indication is obtained, the test shall be repeated. When any short indication is again obtained the tube will be rejected as an inoperative. The statement in "Inspection" Instructions for Electron Tubes", paragraph 5.3.6.1, which reads "*any tube which shows a grid current reading of 1.0 uAdc or twice the maximum limit for grid current, whichever is greater, shall be considered an inoperative" shall not apply.
- c. Determine the number of defective tubes at the 100 hour period.
- d. If more than the allowable number of defectives occur, declare the lot nonconforming.
- A resubmitted lot must be subjected to all Measurements acceptance Tests except Mechanical Inspection and Vibration tests.
- For Survival Rate Life Test, the equivalent Stability Life Test conditions shall be interpreted as having the same heater voltage (Ef) as the Stability Life Test; and the same interruptions of MIL-E-1 paragraph 4.11.5 as the Intermittent Life Test. The electrode Note 15: voltages shall be such that the average anode current is not less than 80 percent, or more than 100 percent of Stability Life Test average anode current.

Note 16:

Intermittent Life Tests:
a. The first 20 tubes of the Stability Life Test sample which meet the measurements acceptance test limit for those characteristics specified as Intermittent Life Test End Points may be used for the Intermittent Life Test sample. In the event that a second Stability Life Test sample is used, the first 20 tubes from that sample which meet the above conditions shall be used.

- Note 16: b. In the event of failure of the first sample on Intermittent Life Test, take a completely fresh sample (MIL-SID-105 sample size code letter I) and stabilize it in accordance with the conditions of the Stability Life Test. Then select from it the first 40 tubes which meet the measurements acceptance test limits for those characteristics specified as Intermittent Life Test End Points. Subject these 40 tubes to the Intermittent Life Test. Acceptance shall be based on combined results from the first and second samples.
 - c. As an alternate method, the manufacturer may select his life test sample as described in Note 13, paragraph (a).
 - d. Regular Life Test:
 - 1. Regular Life Test shall be conducted for 1000 hours.
 - Regular Life Test acceptance shall be on the basis of the 500 and 1000 hour requirements as indicated on the Specification Sheet.
 - Regular Life Test shall be in effect initially and shall continue in effect until the eligibility criteria for the Reduced Hours Life Test have been met.
 - e. Reduced Hours Life Test:
 - Reduced Hours Life Test shall be conducted for 500 hours and acceptance shall be based on the 500 hour end point limits.
 - Eligibility for Reduced Hours Life Tests: No lot failure due to the 1000 hour life test has occurred in the preceding three (3) consecutive lots.
 - Loss of eligibility for Reduced Hours Life Tests: Two (2) or more 500 hour life test lot failures occurring in the last three (3) consecutive lots.
 - f. The life test sample shall be read at the following times:

0 hours 500 hours (plus 48 hours; minus 24 hours) 1000 hours (plus 48 hours; minus 24 hours; when in force)

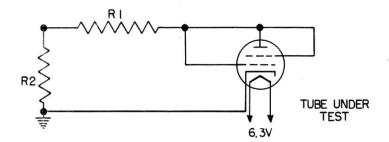
Additional reading periods may be used at the discretion of the electron tube manufacturer.

- g. Acceptance: The lot shall be considered satisfactory for acceptance provided that: The specified allowable defects are not exceeded.
- h. A resubmitted lot must be subjected to all Measurements Acceptance Tests except Mechanical Inspection and Vibration.
- i. Not more than one (1) accidental breakage shall be allowed in the life test sample. If one (1) life test tube is accidentally broken, acceptability of the life test sample shall be based upon the remaining tubes in the sample provided that the broken tube was not known to be a defective.
- Note 17: Envelope Temperature is defined as the highest temperature indicated when using a thermocouple of #40 BS or smaller diameter elements welded to a ring of .025 inch diameter phosphor bronze in contact with the envelope. The envelope temperature requirement will be satisfied if a tube having bogie plate current (\$\frac{1}{2}\$ 5%) under normal test conditions is determined to operate at the minimum specified temperature in any socket position on the life test rack.
- Note 18: Order for Evaluation of Life Test Defects:

 If a tube is defective for more than one attribute characteristic, the characteristic appearing first in the Life Test End Points shall constitute the failure.
- Note 19: An inoperative as referenced in Life Test is defined as a tube having one (1) or more of the following defects: discontinuity (Ref. MIL-E-1, paragraph 4.7.1), shorts (Ref. MIL-E-1, paragraph 4.7.2).

- Note 20: Thirty (30) seconds shall be the maximum time under tost conditions before reading ib.

 There shall be no evidence of amplitude jitters.
- Note 21: The tube shall be tested in the following circuit:



R1 = 10 \(\frac{1}{2} \) 5% noninductive R2 = 15 \(\frac{1}{2} \) 5% noninductive

- (a) A dummy calibrating tube containing a $5 \neq 5\%$ ohm noninductive resistance shall be used for calibration and maintenance. The calibrated pulse voltage amplitude shall be within specified values over 80% of the top portion of the pulse. No portion shall exceed 198 volts maximum amplitude.
- (b) The tube shall be preheated at Ef=6.3V. The tube shall be transferred within 3 seconds to the test socket and preheated with Ef=6.3V only for a minimum of 5 seconds immediately before the application of pulse voltage.
 - (c) The maximum testing time is 3 seconds.
- Note 22: Inoperatives shall be defined in accordance with the requirements of the Short and Continuity Test, MIL-E-1, paragraph 4.7.5., and "Inspection Instructions for Electron Tubes", dated 5 Oct. 1955, paragraph 5.3.6. The statement "*any tube which shows a grid current reading of 1.0 uAdc or twice the maximum limit for grid current, whichever is greater, shall be considered as an inoperative" shall not apply.
- Note 23: Read electrode insulation between G2 and plate with all other elements floating.
- Note 24: Preheat using Ef=5.7 V.
- Note 25: Preheat for 15 minutes under the following conditions: Ef=7.0V, Epp=220 Vac; Eccl = Ecc2 =0; Rgl= 10 Meg; Ib=100 mAdc. Two (2) seconds shall be the maximum time between preheat and test.
- Note 26: Eggl supply shall be in phase with Epp supply and Egg2 supply 1800 out of phase with Epp supply.
- Note 27: Vary Egg2 supply and read Egg2 at which conduction occurs.
- Note 28: Phase of grid voltage adjusted to provide start of conduction at peak applied anode voltage.
- Note 29: Average life is equal to 90% minimum calculated as 4.3.1 of the "Inspection Instructions for Electron Tubes".
- Note 30: At the end of 100 hours, those tubes which meet the initial test requirements shall not be considered as having undergone a destructive test.

- Note 31: Thirty seconds maximum in the operation test socket is permitted before reading. There shall be no evidence of amplitude jitter. The tube shall be tested in the circuit shown in Figure 1. The circuit constants shall be so choser that: at epy = 1000 v. under resonant charging conditions, dik/dt = 100 a/us minimum, tp = 2.0 us \(\frac{1}{2} \) 10%, prr = 500pps. The grid pulse characteristics at egy = 100v shall be: tp = 2.0us maximum, tr = 0.5 us minimum, driver impedance = 500 ohms minimum.
- Note 32: Adjust epy for ib = 20 a initially, and maintain this epy value throughout the life test. The tube shall be tested in the circuit shown in Figure 1. The circuit constants shall be so chosen that: at epy = 500 v under resonant charging conditions, dik/dt = 100 a/us minimum, tp = 2.0 us / 10%, prr = 1000 pps. The grid pulse characteristics at egy = 100 v shall be: tp = 2.0 us maximum, tr = 0.5 us minimum, driver impedance = 500 ohms minimum.
- Note 33: Reference specification shall be of the issue in effect on the date of invitation for bid.

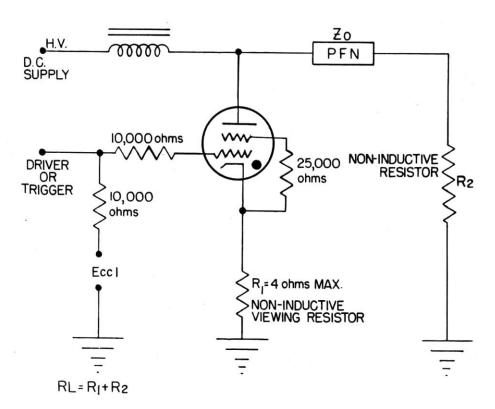


Fig. 1

	Specification MOS/CV.4018	SEC	RITY
->	incorporating MIL/E/1/83A Issue 2 dated 26-2-57. & BS:LLB	Specification	<u>Valve</u>
	To be read in conjunction with K.1006	UNCLASSIFIED	UNCLASSIFIED

-> indicates a change

TYPE OF VALVE - Ges-filled Tetrode (Reliable) CATHODE - Indirectly Heated			_	RKING K1001/4				
ENVELOPE - Glass, unmetallised		additional marking 5727/2D21W						
PROTOTYPE - 5727/2D21W			214	1/202111				
RATINGS								
		Relay, atrolle		Modulator	Notes			
Heater Voltage Heater Current Max Feak AC Anode Voltage Max Peak Forward Anode Voltage Wax Anode P.I.V. Max G2 Voltage (Conduction) Max G4 Voltage (Conduction) Max Peak G2 Voltage (Non-conduction) V)		6.3 ± 0.6 650 1300 -10 -10		6.3 ±10% 0.6 500 500 100 -10 -10	В			
Max Peak G1 Voltage (Non-conduction) Max Peak G1 Voltage (Non-conduction) Max Peak Heater-Cathode Voltage Max G1 Circuit Resistance Min G2 Series Resistance Mx G2 Series Resistance Mx G2 Series Resistance Mx Peak Cathode Current (k)		-100 -100 to 10	+25	-100 0 0.5 2 25				
Max Mean Cathode Current (mi) Max Peak G2 current (mA) Max Peak G1 current (mA) Max Mean G2 Current (mi) Max Mean G1 Current (mi) Max Pulse Duration (us) Max Rate of Rise of Cathode Current (i) Max p.r.f. (pps)		100 10 10		10 20 20 20 5 100 500	0 00			
Max Duty Cycle Max Ambient Temperature Range Min Cathode Heating Time (Sec)		-75 to	100	0.001 -75 to +90 10				
NOTES			Connec	tions				
A. All limiting values are absolute.		Pin	El	ectrode				
B. After the completion of a pulse, a 20 uSec delay is required before a positive voltage of more than 10V is applied.		1 2 3 4 5 6	g1 control grid k cathode h heater h heater g2 auxiliary grid a anode					
C. Average over any interval of 30 seconds minimum.	Average over any interval of 7 g2 auxiliary grid							
See BS.448 Section B7G/2.1.3								
Dimension mm A. Seated height C. Diameter D Overall length				16.0	ax. 4.0 9.0 1.0			